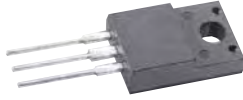


ITO-220AB

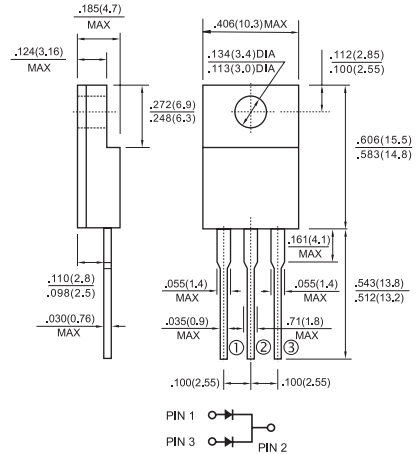


Features

- ◇ Glass passivated chip junction.
- ◇ High efficiency, Low VF
- ◇ High current capability
- ◇ High reliability
- ◇ High surge current capability
- ◇ Low power loss

Mechanical Data

- ◇ Cases: ITO-220AB molded plastic
- ◇ Epoxy: UL 94V-0 rate flame retardant
- ◇ Polarity: As marked
- ◇ High temperature soldering guaranteed:
260 °C /10 seconds 0.25", (6.35mm) from case.
- ◇ Mounting position: Any
- ◇ Weight: 2.24 grams
- ◇ Mounting torque: 5 in – 1bs. max.



Dimensions in inches and (millimeters)

Maximum Ratings and Electrical Characteristics

Rating at 25 °C ambient temperature unless otherwise specified.
Single phase, half wave, 60 Hz, resistive or inductive load.
For capacitive load, derate current by 20%

Type Number	Symbol	FRF 501G	FRF 502G	FRF 503G	FRF 504G	FRF 505G	FRF 506G	FRF 507G	Units
Maximum Recurrent Peak Reverse Voltage	V_{RRM}	50	100	200	400	600	800	1000	V
Maximum RMS Voltage	V_{RMS}	35	70	140	280	420	560	700	V
Maximum DC Blocking Voltage	V_{DC}	50	100	200	400	600	800	1000	V
Maximum Average Forward Rectified Current See Fig. 1	$I_{(AV)}$	5.0							A
Peak Forward Surge Current, 8.3 ms Single Half Sine-wave Superimposed on Rated Load (JEDEC method)	I_{FSM}	30							A
Maximum Instantaneous Forward Voltage @2.5A	V_F	1.5							V
Maximum DC Reverse Current @ $T_C=25\text{ }^\circ\text{C}$ at Rated DC Blocking Voltage @ $T_C=125\text{ }^\circ\text{C}$	I_R	5.0 100							μA μA
Maximum Reverse Recovery Time (Note1)	T_{rr}	150			250	500		nS	
Typical Junction Capacitance (Note 2)	C_j	140							pF
Typical Thermal Resistance (Note 3)	$R_{\theta JC}$	4.0							$^\circ\text{C/W}$
Operating and Storage Temperature Range	T_J, T_{STG}	-65 to +150							$^\circ\text{C}$

- Notes:
1. Reverse Recovery Test Conditions: $I_F=0.5\text{A}$, $I_R=1.0\text{A}$, $I_{RR}=0.25\text{A}$
 2. Measured at 1MHz and Applied Reverse Voltage of 4.0 Volts D.C.
 3. Mount on Heatsink Size 2" x 3" x 0.25" Al-Plate.

RATINGS AND CHARACTERISTIC CURVES (FRF501G THRU FRF507G)

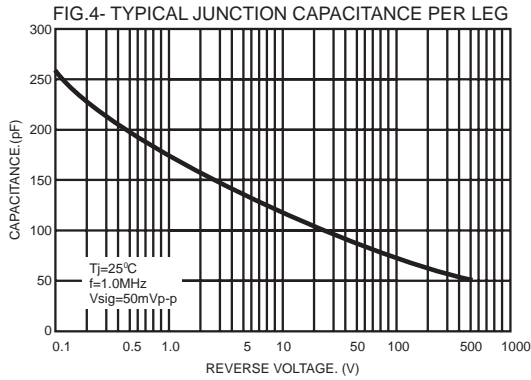
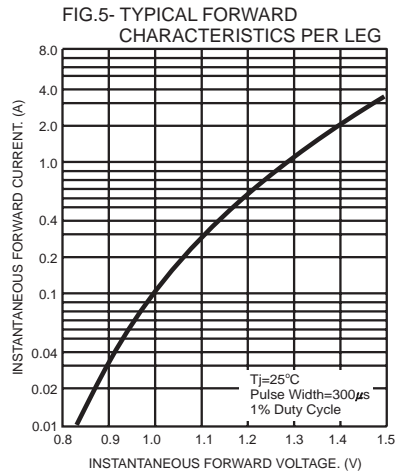
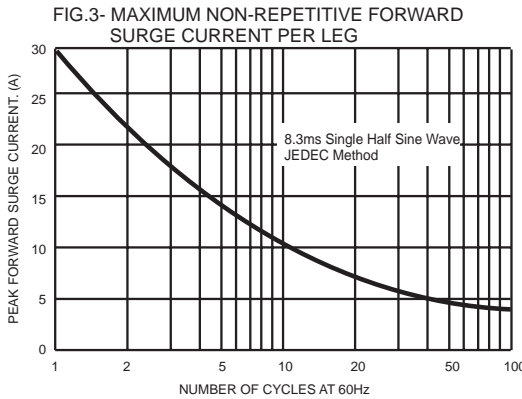
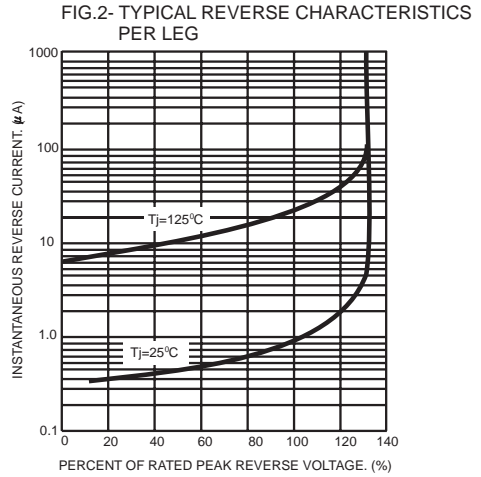
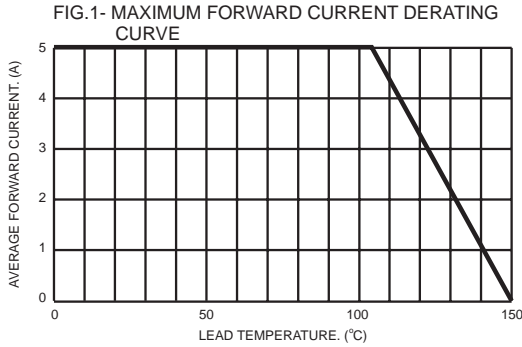


FIG.6- REVERSE RECOVERY TIME CHARACTERISTIC AND TEST CIRCUIT DIAGRAM

